



FOR IMMEDIATE RELEASE

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**AEHR TEST SYSTEMS ANNOUNCES NEW MASSIVELY  
PARALLEL TEST & BURN-IN SYSTEM**

**Fremont, CA (July 22, 2003)** – Aehr Test Systems (Nasdaq: AEHR), a leading supplier of semiconductor test and burn-in equipment, today announced the availability of the MTX-P, a new addition to its MTX family of products for massively parallel testing and burn-in of DRAMs and other memory ICs. The MTX-P has new and improved signal and power supply electronics, allowing the system throughput to increase by more than 50 percent. The MTX-P system has the capability to process over 12,000 of the latest DDR DRAMs simultaneously.

“We believe this higher capacity MTX-P will improve our competitive position in the extremely cost-sensitive DRAM market,” said Bill Barraclough, Senior Director of Product Marketing. “The MTX-P maintains software, program, and system interface compatibility with our existing systems, accommodating seamless implementation by our installed base of customers.”

The MTX-P can use the standard MTX PTB (Parallel Test Board) or the new, larger PTB-400. The improved electronics of the MTX-P and the PTB-400 can be combined to enable testing of up to 16,000 I/O pins per PTB-400.

**About Aehr Test Systems**

Headquartered in Fremont, California, Aehr Test Systems is a leading worldwide provider of systems for burning-in and testing DRAM and logic integrated circuits and has an installed base of more than 2,000 systems worldwide. Aehr Test has developed and introduced several innovative products, including the FOX<sup>TM</sup>, MTX, MAX3 and MAX4 systems and the DiePak<sup>®</sup> carrier. The FOX system is a full wafer contact test and burn-in system. The MTX system is a massively parallel test system designed to reduce the cost of memory testing by performing both test and burn-in on thousands of devices simultaneously. The MAX system can effectively burn-in and functionally test complex devices, such as digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company’s website at [www.aehr.com](http://www.aehr.com).

**Safe Harbor Statement**

This release contains forward-looking statements that involve risks and uncertainties relating to projections regarding industry growth, market penetration into the competitive DRAM market, customer demand for Aehr Test's products and expectations of future sales and performance of the MTX-P. Actual results may vary from projected results. These risks and uncertainties include, without limitation, acceptance by customers of the FOX, MTX, MAX and DiePak technologies, market acceptance of new products, ability of new products to meet customer needs or perform as described, strong competition in our markets, the risks associated with bringing new products to market and the potential emergence of alternative technologies, which could adversely affect demand for Aehr Test's products in calendar year 2003. See Aehr Test's recent 10-K and 10-Q reports filed with the SEC for a more detailed description of the risks facing our business. The Company disclaims any obligation to update information contained in any forward-looking statement to reflect events or circumstances occurring after the date of this press release.

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